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(12) **United States Design Patent**
Kojima et al.

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(54) **ELECTRON MICROSCOPE**

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(**) Term: **15 Years**

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(30) **Foreign Application Priority Data**

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(51) **LOC (13) Cl.** **16-06**
(52) **U.S. Cl.**
USPC **D16/131**
(58) **Field of Classification Search**
USPC D10/70, 109.1, 109.2, 81; D16/134, 130, D16/131, 132, 135, 136, 137, 202–208, D16/245, 219; D24/120, 113, 118, 119, D24/121, 122, 124, 125, 128
CPC ... G01C 3/00; G01C 3/02; G01C 3/04; G01C 3/06; G01C 3/08; G01C 3/085; G01C 3/10; G01C 3/12; G01C 3/16; G01C 3/18; G01C 3/20; G01C 3/22; G01C 3/24; G01C 3/26; G01C 3/28; G01C 3/30; G01C 3/32; B60Q 1/04; B60Q 1/26; F21S 8/026; F21S 8/04; F21V 29/004; F21V 21/02; F21V 21/04; F21V 29/2212; F21Y 2101/02; G02B 27/026; G02B 23/16; G02B 2003/0093; G02B 3/04; H04J 11/00; H04J 13/00; E06B 9/24; G03B 17/02; C03B 2215/46
See application file for complete search history.

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(Continued)

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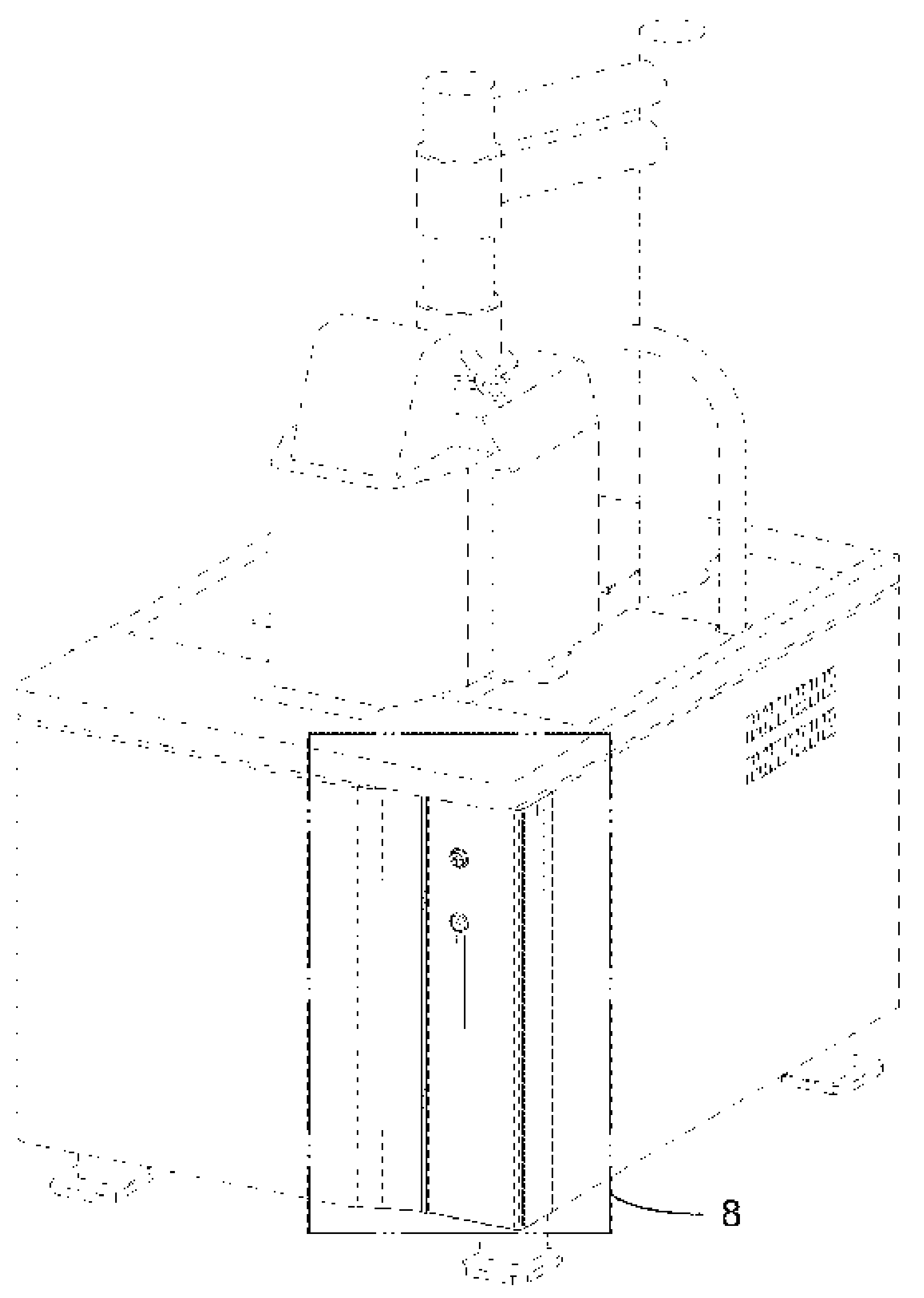
(57) **CLAIM**

The ornamental design for an electron microscope, as shown and described.

DESCRIPTION

FIG. **1** is a front, top and right side perspective view of an electron microscope according to the design;
FIG. **2** is a front view thereof;
FIG. **3** is a right side view thereof;
FIG. **4** is a left side view thereof;
FIG. **5** is a rear view thereof;
FIG. **6** is a top plan view thereof;
FIG. **7** is a bottom plan view thereof;
FIG. **8** is an enlarged view of the portion shown in BOX **8** in FIG. **1**;
FIG. **9** is cross-sectional view taken along line **9-9** of FIG. **2**; and,
FIG. **10** is an enlarged view of the portion shown in BOX **10** in FIG. **9**.
The dashed broken lines in the drawings show portions of the electron microscope that form no part of the claimed design. The dot-dash broken lines in the drawings indicate boundaries of the claimed subject matter that form no part of the claimed design. The dot-dot-dash broken lines in the drawings indicate boundaries of the view indicators that form no part of the claimed design.

1 Claim, 10 Drawing Sheets



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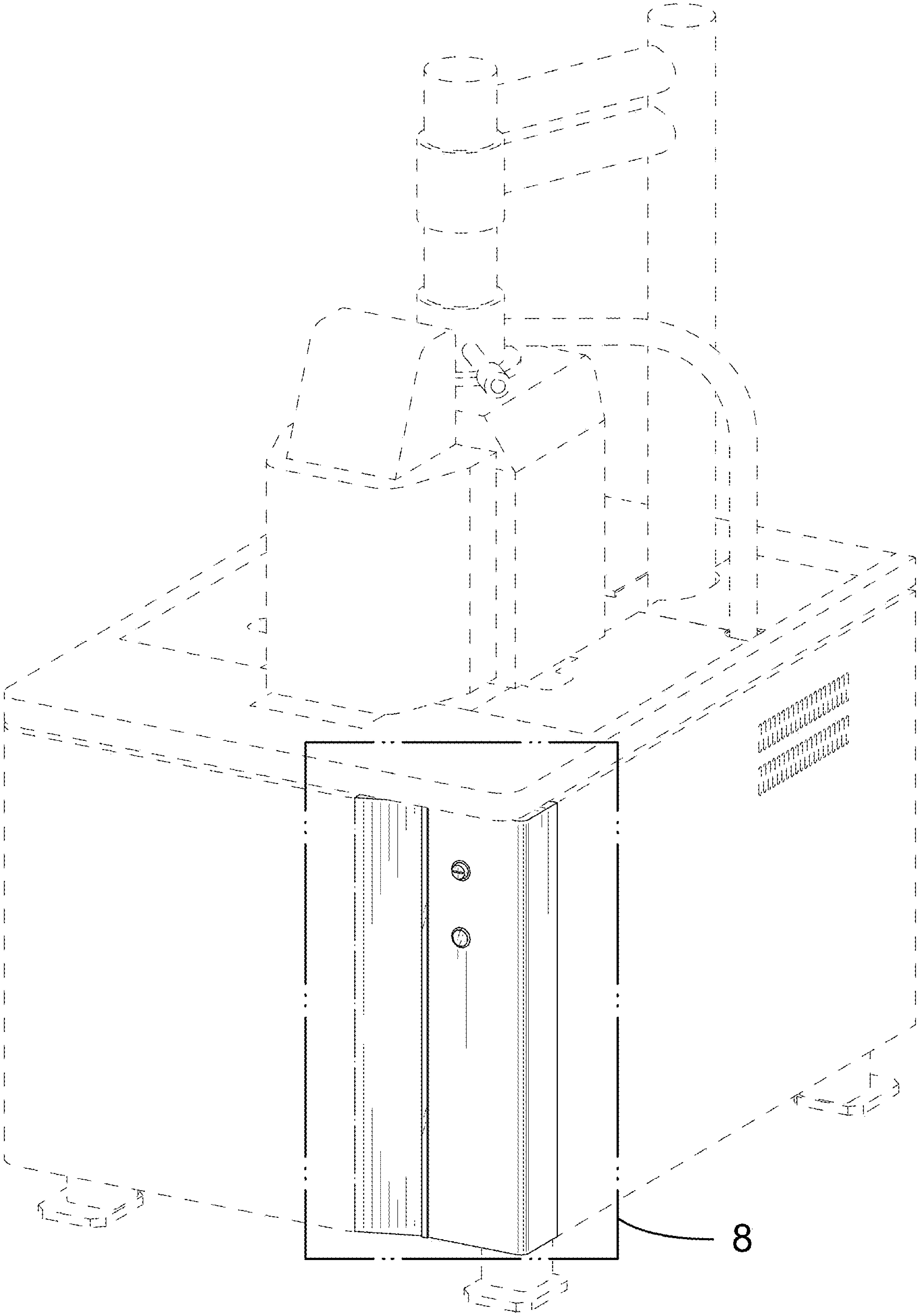

FIG. 1

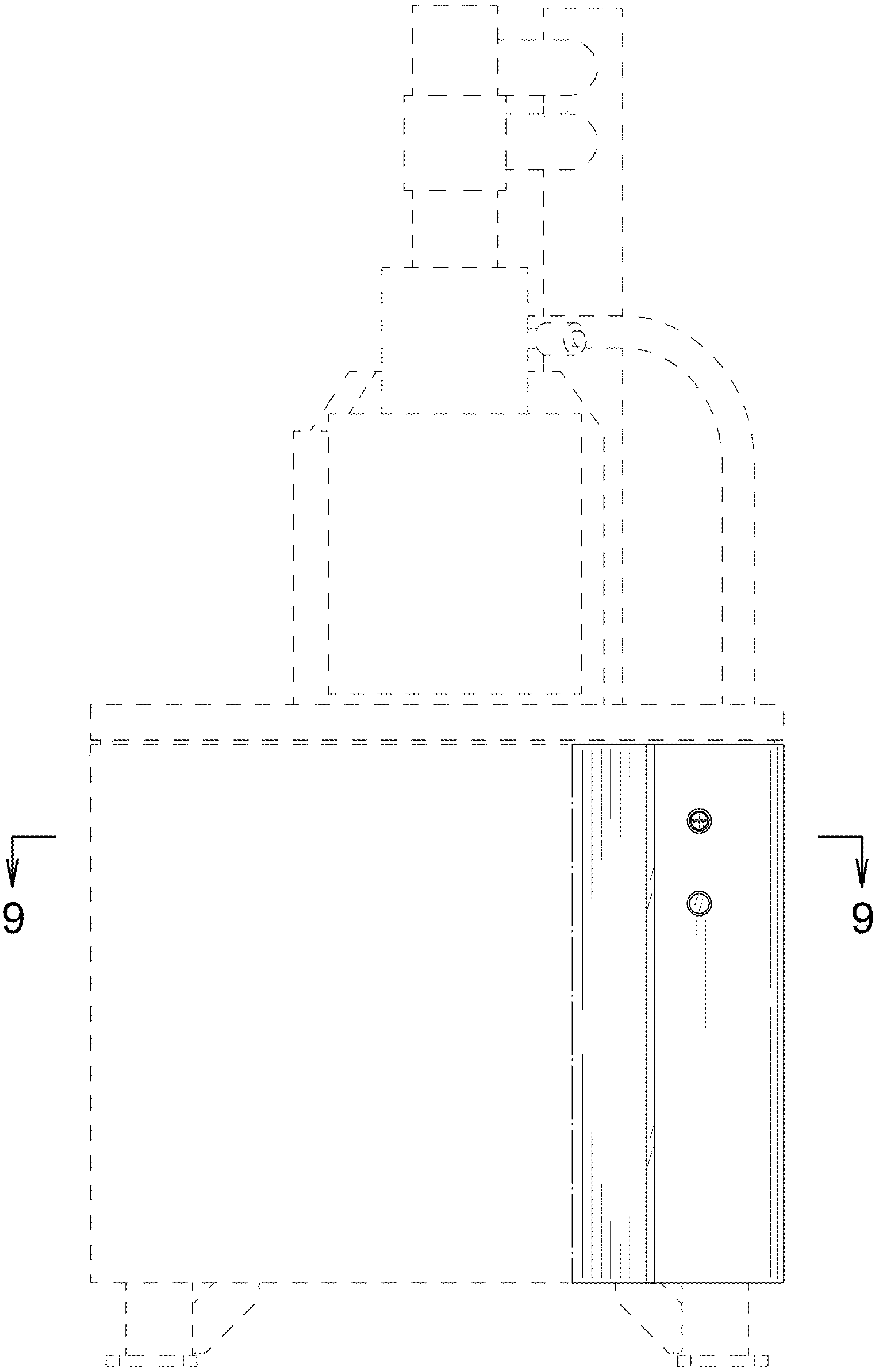

FIG. 2

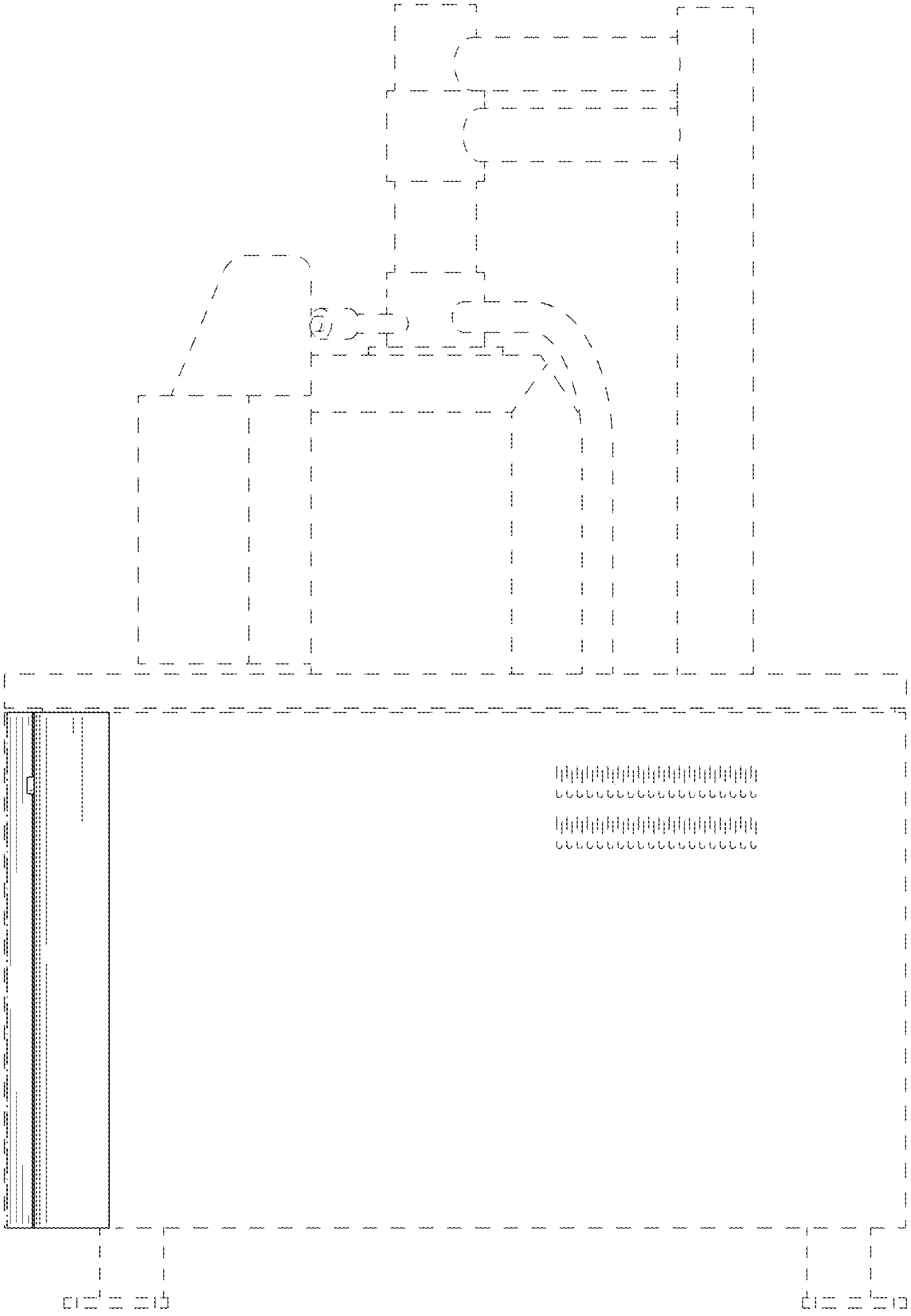

FIG. 3

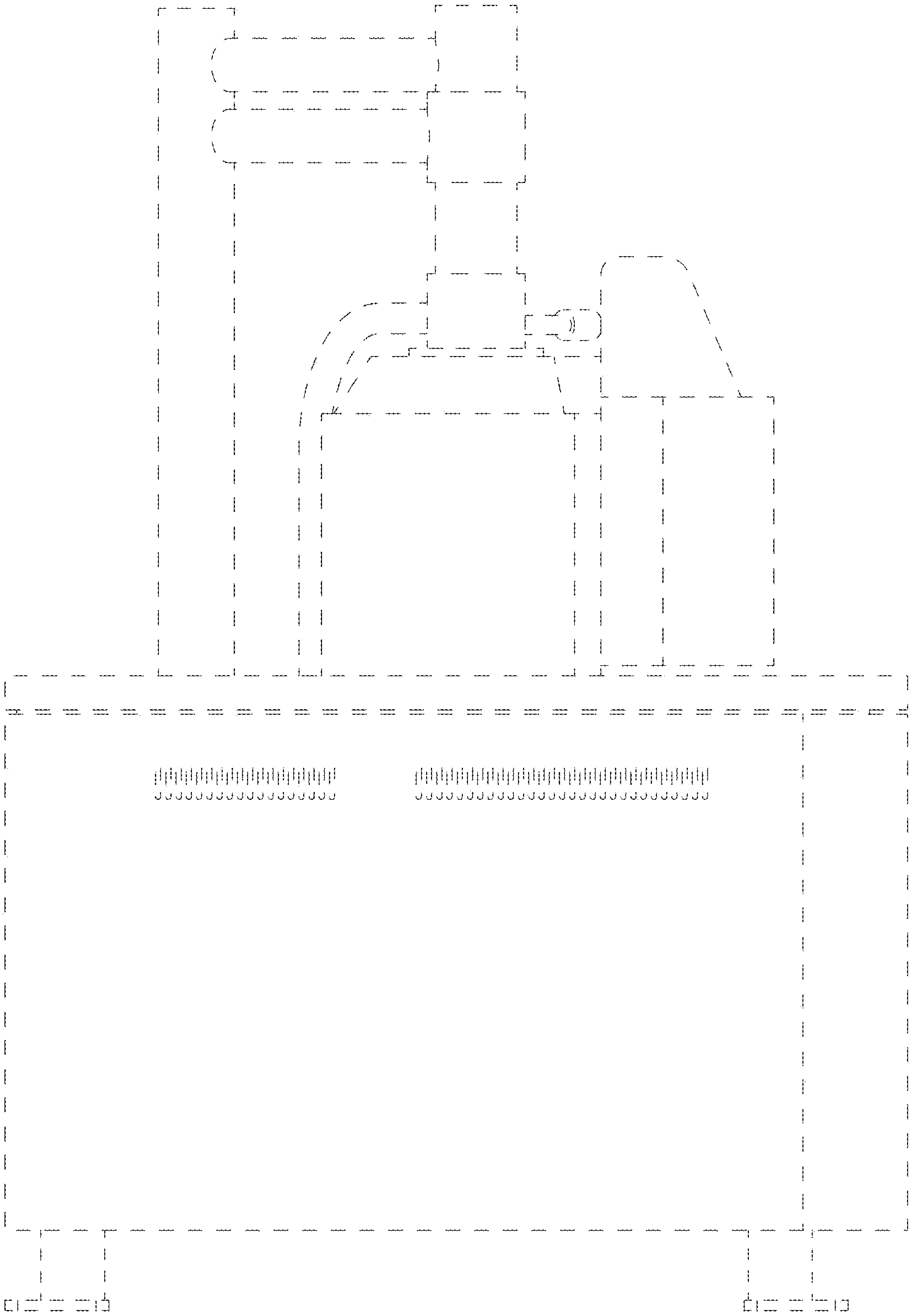

FIG. 4

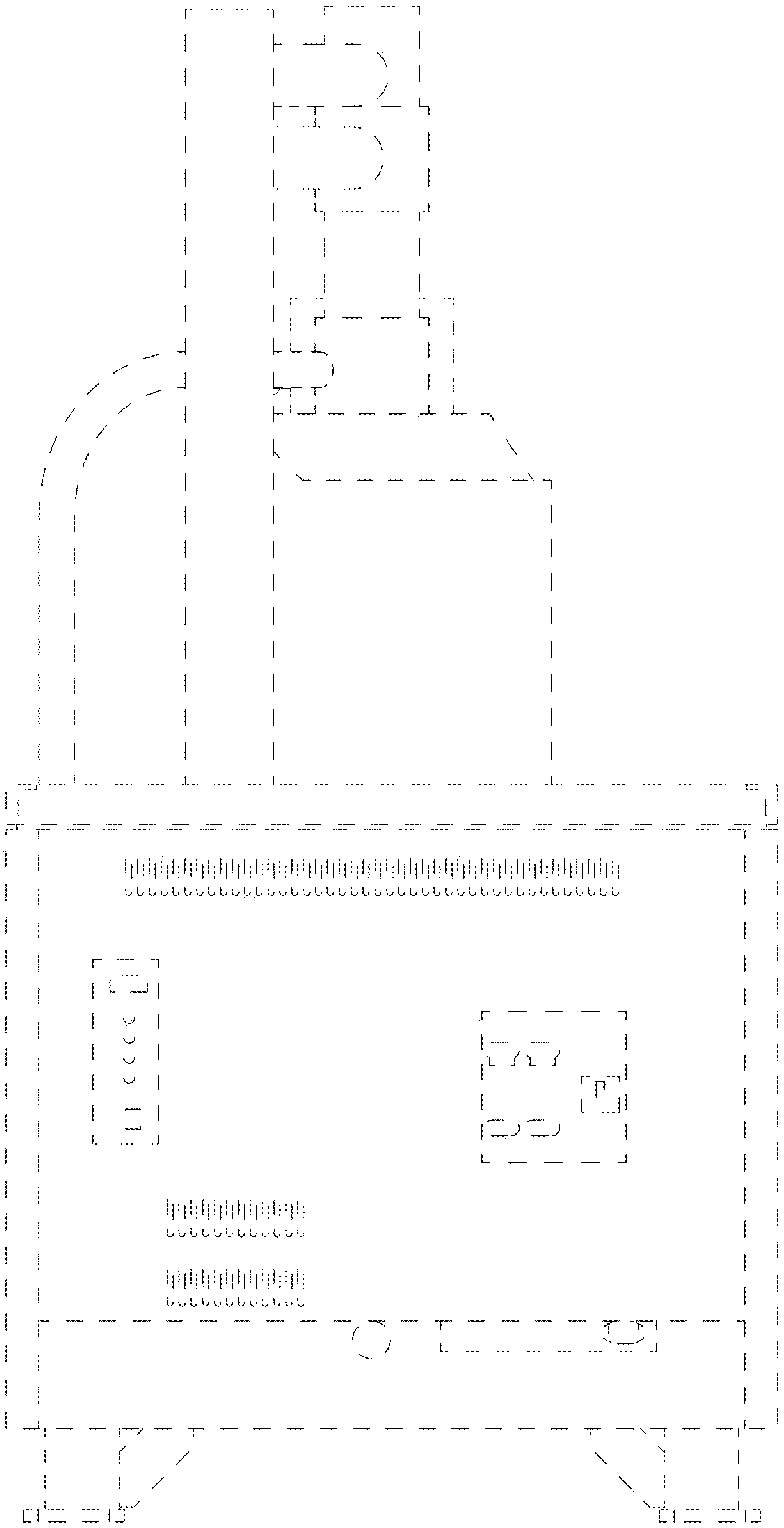

FIG. 5

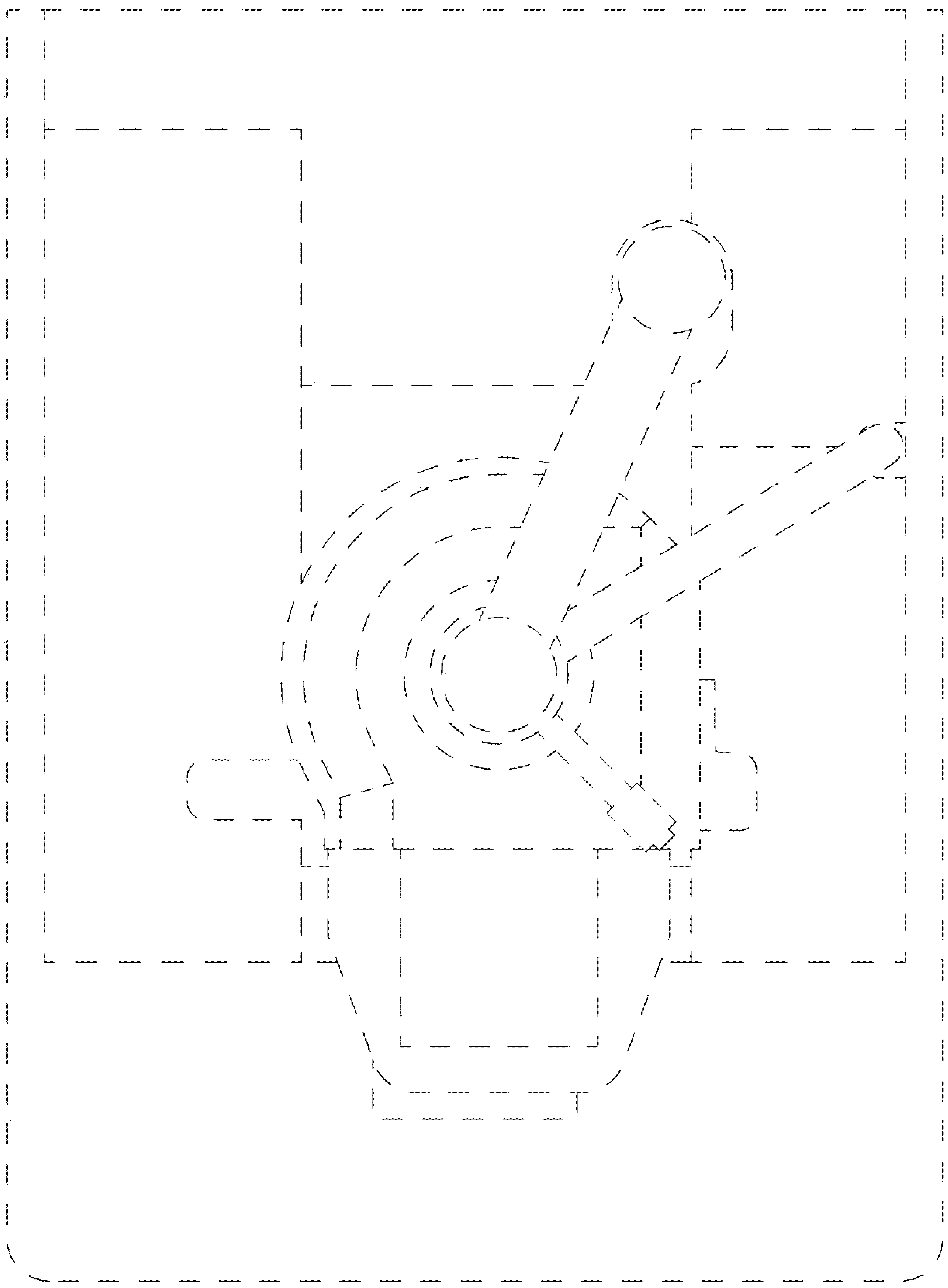

FIG. 6

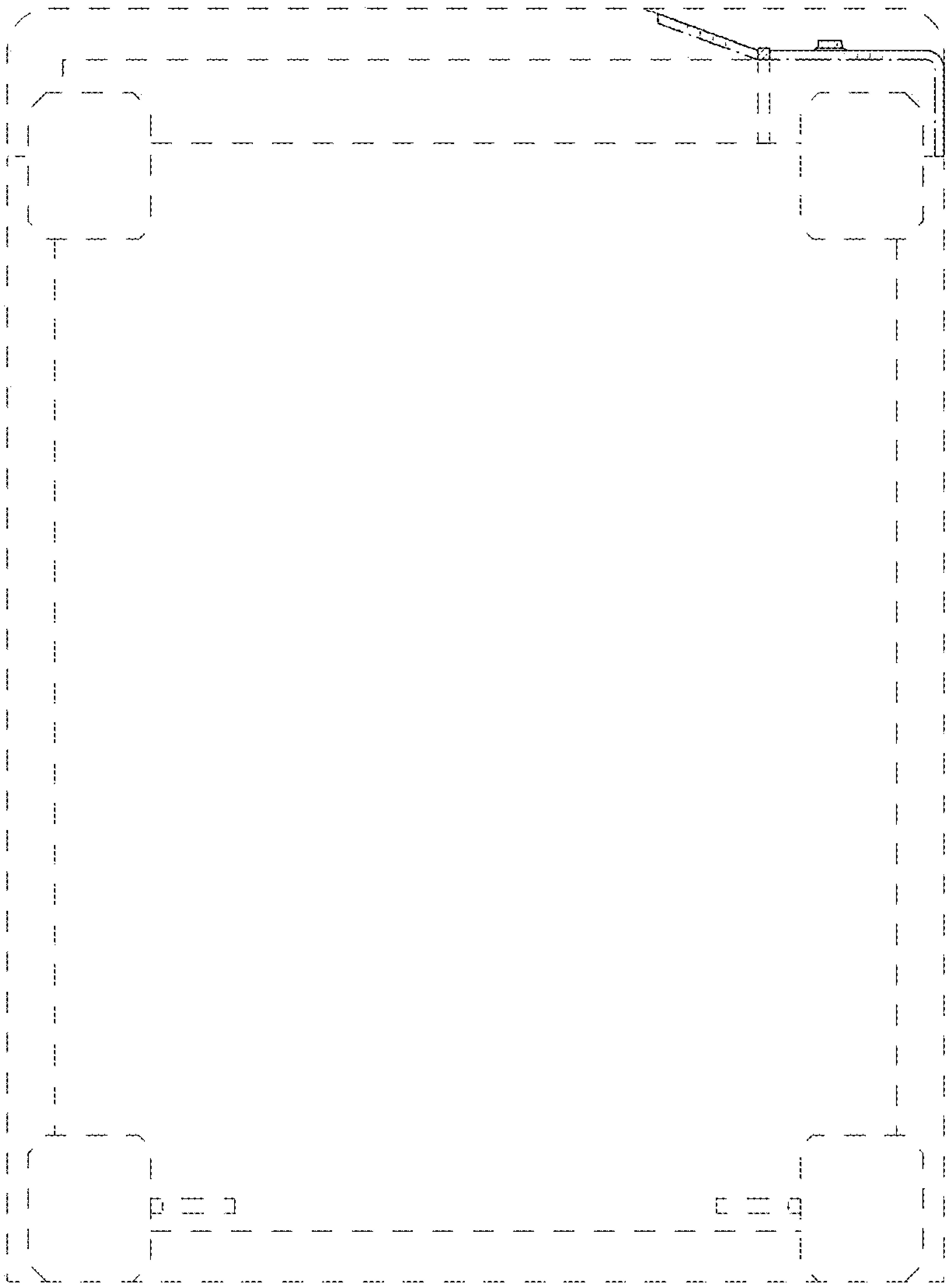

FIG. 7

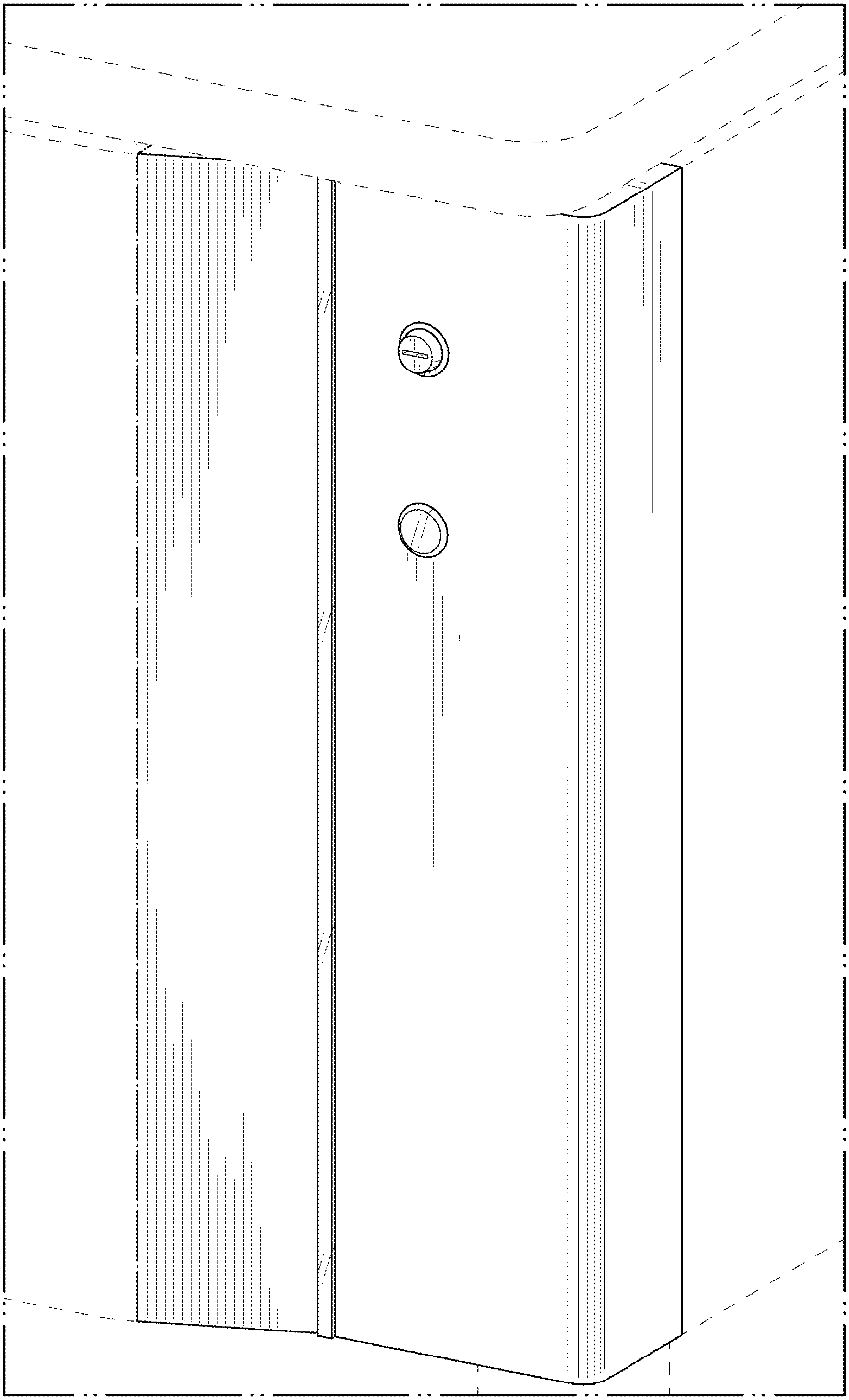

FIG. 8

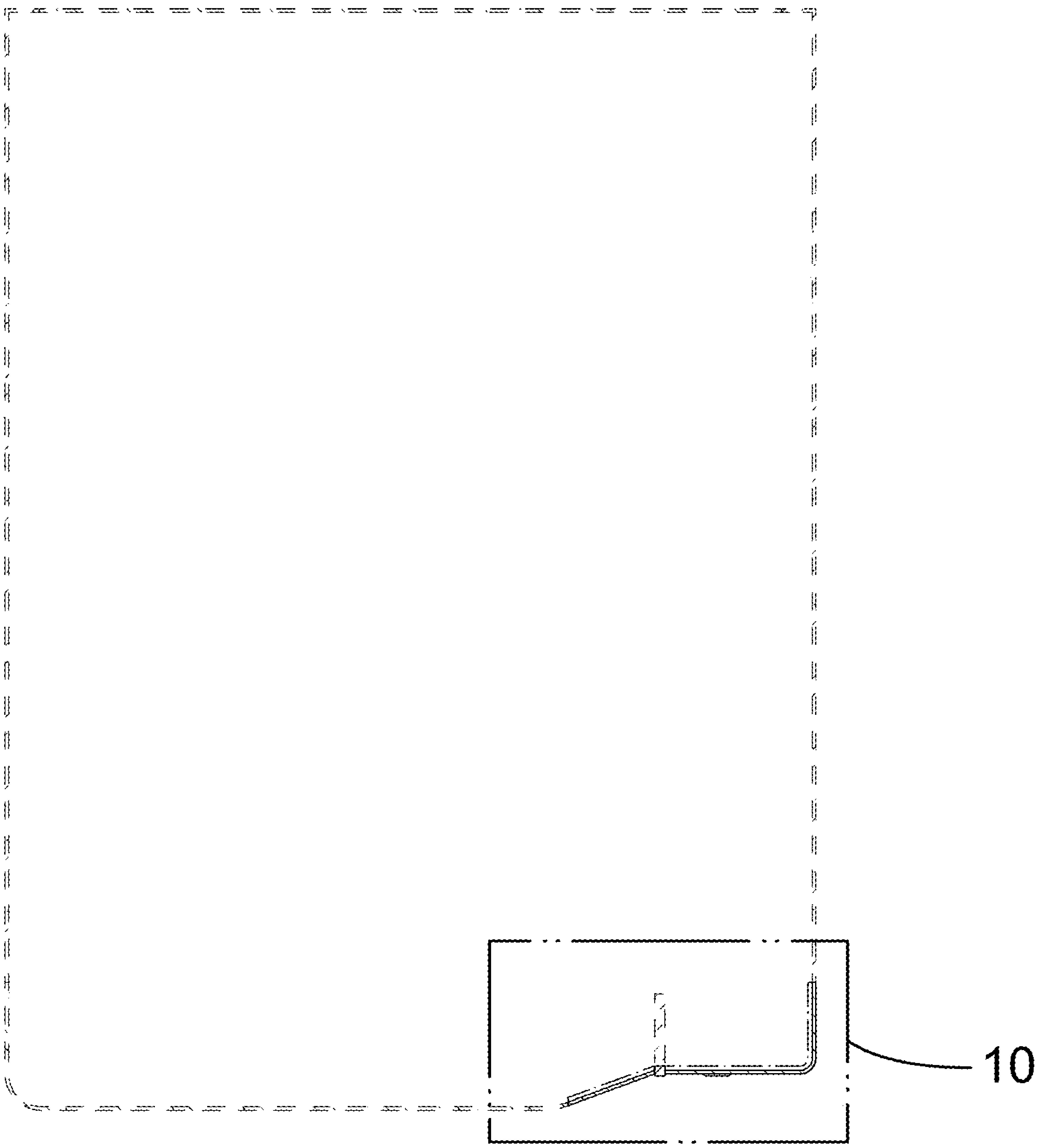

FIG. 9

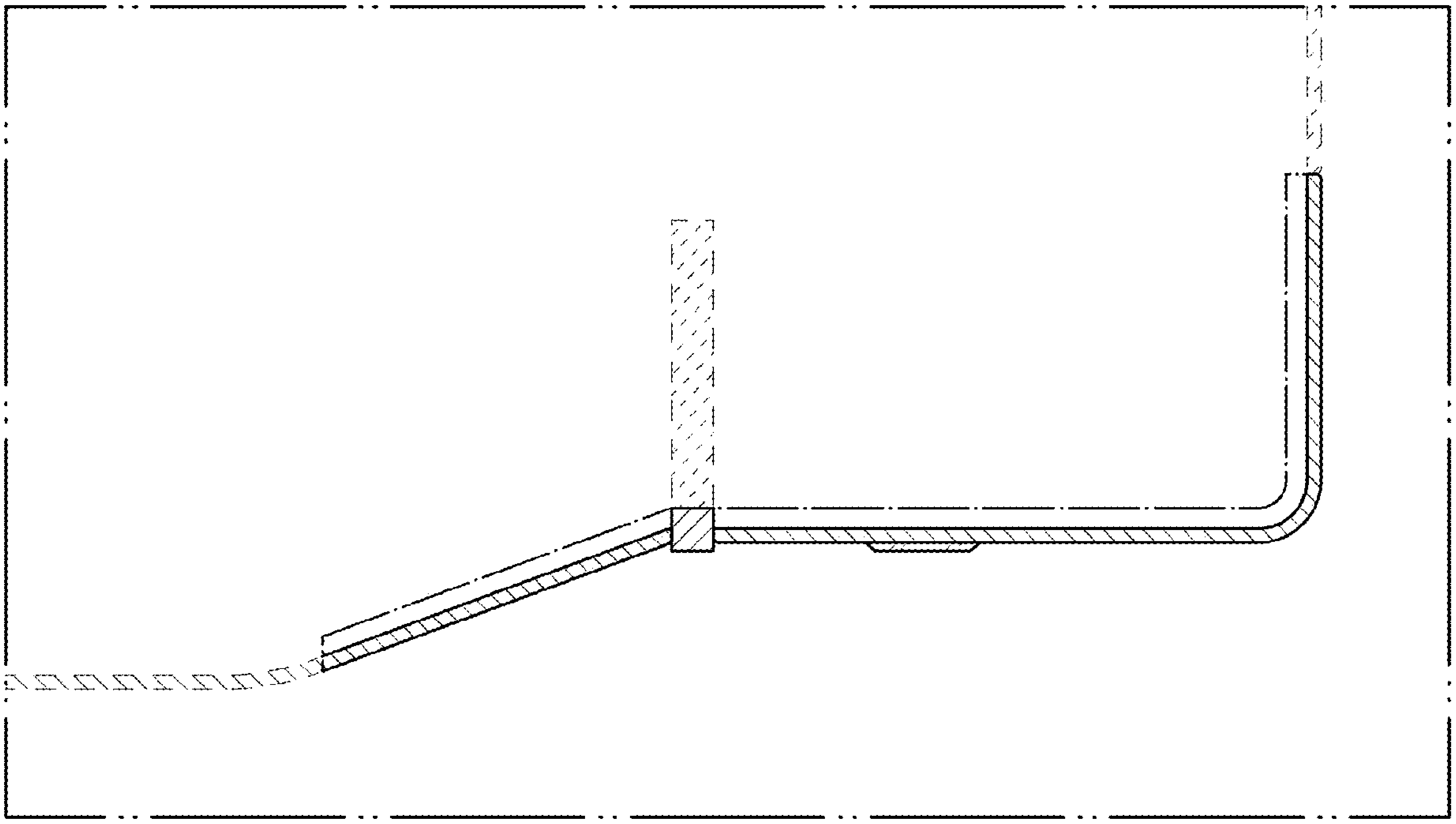

FIG. 10